FAIRCHILD

SEMICONDUCTOR®

FDI8441

N-Channel PowerTrench[®] MOSFET 40V, 80A, 2.7m Ω

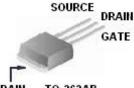
Features

- Typ $r_{DS(on)}$ = 2.2m Ω at V_{GS} = 10V, I_D = 80A
- Typ Q_{g(10)} = 215nC at V_{GS} = 10V
- Low Miller Charge
- Low Q_{rr} Body Diode
- UIS Capability (Single Pulse and Repetitive Pulse)
- Qualified to AEC Q101
- RoHS Compliant

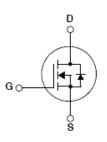
Applications

- Automotive Engine Control
- Powertrain Management
- Solenoid and Motor Drivers
- Electronic Steering
- Integrated Starter / Alternator
- Distributed Power Architectures and VRMs
- Primary Switch for 12V Systems





DRAIN TO-262AB (FLANGE) FDI SERIES



July 2007

Symbol	Parameter		Ratings	Units
V _{DS}	Drain to Source Voltage		40	V
V _{GS}	Gate to Source Voltage		±20	V
	Drain Current Continuous (T _C < 160°C, V _{GS} = 10V)		80	
I _D	Continuous (T_{amb} = 25°C, V_{GS} = 10V, with $R_{\theta JA}$ = 43°C/W)		26	Α
	Pulsed	See Figure 4		
E _{AS}	Single Pulse Avalanche Energy (N	lote 1)	947	mJ
D	Power dissipation		300	W
P _D	Derate above 25°C		2	W/ºC
T _J , T _{STG}	Operating and Storage Temperature		-55 to 175	°C

Thermal Characteristics

$R_{ ext{ heta}JC}$	Thermal Resistance Junction to Case	0.5	°C/W
$R_{\theta JA}$	Thermal Resistance Junction to Ambient (Note 2	2) 62	°C/W
R_{\thetaJA}	Thermal Resistance Junction to Ambient, 1in ² copper pad area	43	°C/W

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDI8441	FDI8441	TO-262AB	Tube	NA	50 units

Electrical Characteristics $T_J = 25^{\circ}C$ unless otherwise noted

I Parameter Test Conditions Min Typ Max	Symbol	Sy	Parameter	Test Conditions	Min	Тур	Мах	Units
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Off Characteristics

B _{VDSS}	Drain to Source Breakdown Voltage	I _D = 250mA, V	_{GS} = 0V	40	-	-	V
	Zero Gate Voltage Drain Current	V _{DS} = 32V		-	-	1	
DSS	Zero Gale volage Drain Current	$V_{GS} = 0V$	T _J = 150°C	-	-	250	μA
I _{GSS}	Gate to Source Leakage Current	V_{GS} = ±20V		-	-	±100	nA

On Characteristics

V _{GS(th)}	Gate to Source Threshold Voltage	V_{DS} = V_{GS} , I_D = 250 μ A	2	2.8	4	V
		I _D = 80A, V _{GS} = 10V	-	2.2	2.7	
r _{DS(on)}	Drain to Source On Resistance	I _D = 80A, V _{GS} = 10V, T _J = 175°C	-	3.8	4.7	mΩ

Dynamic Characteristics

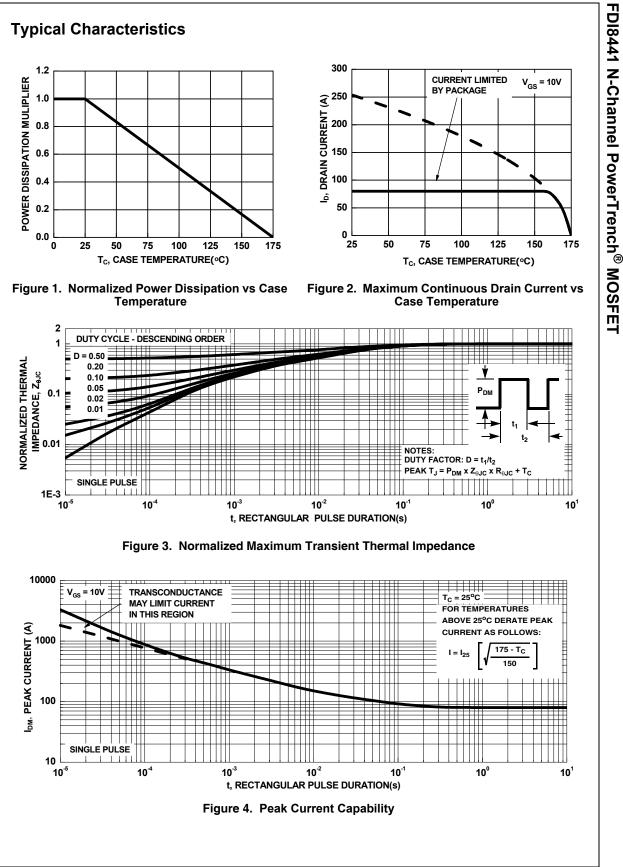
C _{iss}	Input Capacitance	— V _{DS} = 25V, V _{GS} = 0V, f = 1MHz		-	15000	-	pF
C _{oss}	Output Capacitance			-	1250	-	pF
C _{rss}	Reverse Transfer Capacitance			-	685	-	pF
R _G	Gate Resistance	V _{GS} = 0.5V, f = 1MHz		-	1.1	-	Ω
Q _{g(TOT)}	Total Gate Charge at 10V	V _{GS} = 0 to 10V		-	215	280	nC
Q _{g(TH)}	Threshold Gate Charge	V_{GS} = 0 to 2V	V _{DD} = 20V	-	29	38	nC
Q _{gs}	Gate to Source Gate Charge		I _D = 35A	-	60	-	nC
Q _{gs2}	Gate Charge Threshold to Plateau		l _g = 1mA	-	32	-	nC
Q _{gd}	Gate to Drain "Miller" Charge			-	49	-	nC

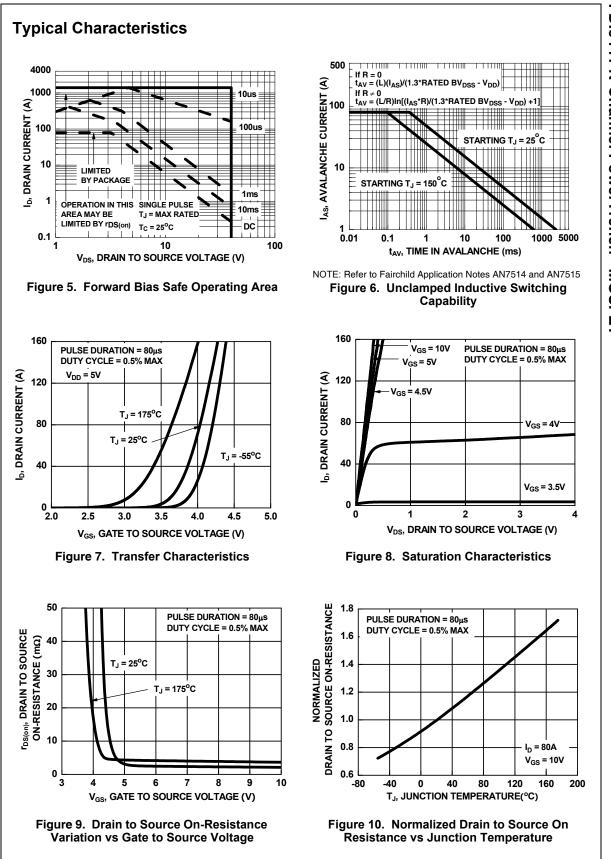
Symbol	Parameter	Test Conditions	Min	Тур	Мах	Units
Switching	g Characteristics					
t _(on)	Turn-On Time		-	-	77	ns
t _{d(on)}	Turn-On Delay Time		-	23	-	ns
t _r	Turn-On Rise Time	V _{DD} = 20V, I _D = 35A	-	24	-	ns
t _{d(off)}	Turn-Off Delay Time	$V_{GS} = 10V, R_{GS} = 1.5\Omega$	-	75	-	ns
t _f	Turn-Off Fall Time		-	17.9	-	ns
t _{off}	Turn-Off Time		-	-	147	ns
	urce Diode Characteristics	I _{SD} = 35A		0.8	1.25	V
V _{SD}	Source to Drain Diode Voltage	I _{SD} = 15A	-	0.8	1.0	v
•	Reverse Recovery Time	$I_{\rm F}$ = 35A, di/dt = 100A/µs	-	52	68	ns
t _{rr}			-			

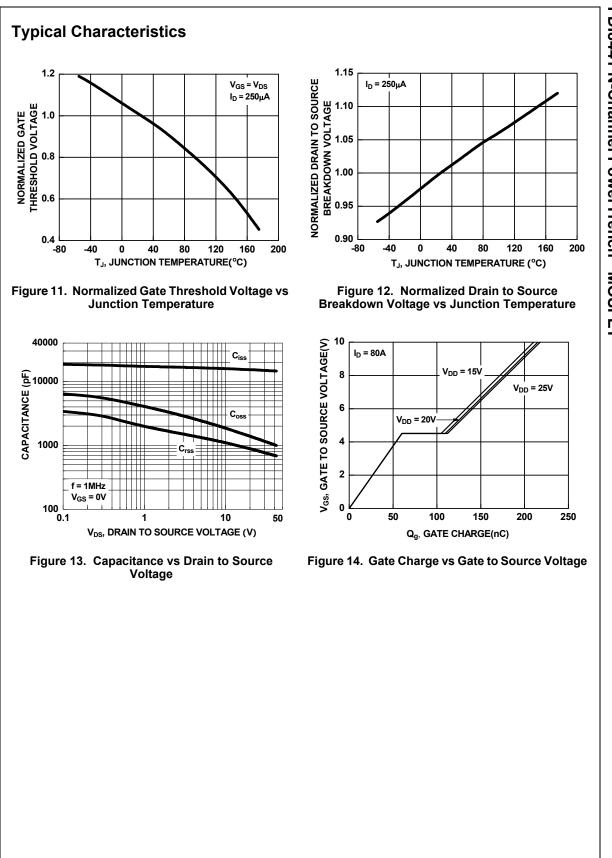
V _{SD} Source to Drain Diode Voltage	I _{SD} = 35A	-	0.8	1.25	V	
V _{SD}	Source to Drain Diode Voltage	I _{SD} = 15A	-	0.8	1.0	V
t _{rr}	Reverse Recovery Time	I _F = 35A, di/dt = 100A/μs	-	52	68	ns
Q _{rr}	Reverse Recovery Charge	I _F = 35A, di/dt = 100A/μs	-	76	99	nC

Notes: 1: Starting $T_J = 25^{\circ}C$, L = 0.46mH, $I_{AS} = 64A$. 2: Pulse width = 100s.

This product has been designed to meet the extreme test conditions and environment demanded by the automotive industry. For a copy of the requirements, see AEC Q101 at: http://www.aecouncil.com/ All Fairchild Semiconductor products are manufactured, assembled and tested under ISO9000 and QS9000 quality systems certification.







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